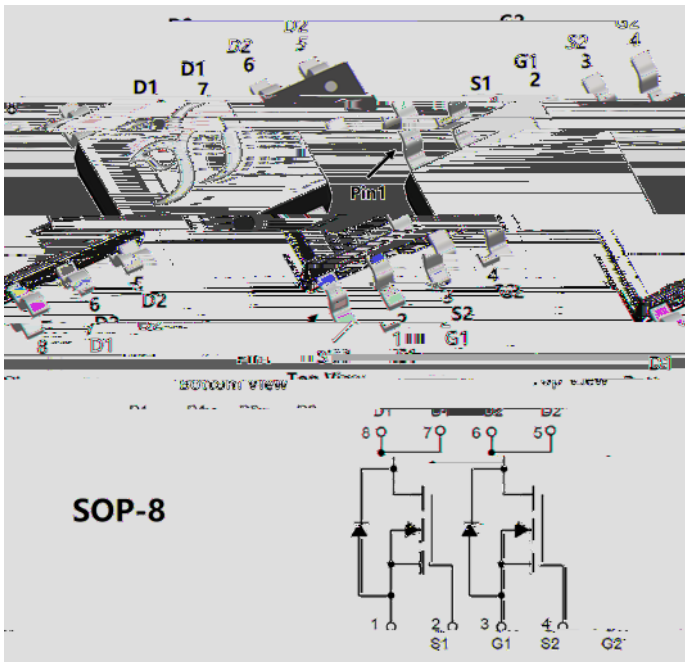




N-Channel Enhancement Mode Field Effect Transistor



SOP-8

Product Summary

• V_{DS}	60V
• I_D	5.0A
• $R_{DS(ON)}$ (at $V_{GS}=10V$)	44mohm
• $R_{DS(ON)}$ (at $V_{GS}=4.5V$)	49mohm

General Description

- Trench Power MV MOSFET technology
- High density cell design for Low $R_{DS(ON)}$
- High Speed switching
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

Applications

- Battery protection
- Load switch
- Power management

■ Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter		Symbol	Maximum	Unit
Drain-source Voltage		V_{DS}	60	V
Gate-source Voltage		V_{GS}	± 20	V
Drain Current	$T_A=25^\circ\text{C}$ @ Steady State	I_D	5.0	A
	$T_A=70^\circ\text{C}$ @ Steady State		4.0	
	$T_A=125^\circ\text{C}$ @ Steady State		2.2	
Pulsed Drain Current ^A		I_{DM}	25	A
Total Power Dissipation @ $T_A=25^\circ\text{C}$		P_D	3.1	W
Thermal Resistance Junction-to-Ambient @ Steady State ^B		$R_{\theta JA}$	40.3	$^\circ\text{C/W}$
Avalanche energy ^C		EAS	30.25	mJ

Junction and Storage Temperature Range

 T_J, T_{STG}

-55 +150

3% OUTER CARTON

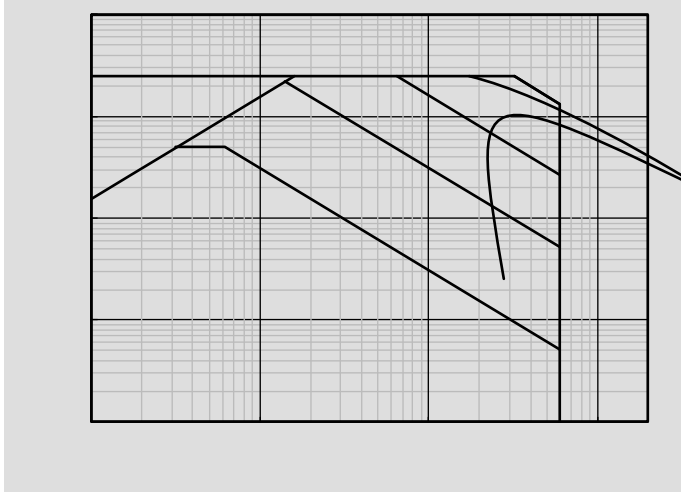
					QUANTITY(pcs)	DELIVERY MODE
YJS05N06A	F2	Q05N06	4000	8000	64000	13" reel



YJS05N06A

■ Electrical Characteristics ($T_j=25$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	60			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=60V, V_{GS}=0V$			1	μA
		$V_{DS}=60V, V_{GS}=0V, T_j=125^\circ C$			100	
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D$				





■SOP-8 Package information

SYMBOL	MIN.		
	0.053	0.069	
B	0.004	0.010	
		0.061	
D		0.020	
E			
F			
G	0.050BSC		1.270BSC
H			
J			
K			
	0°		



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